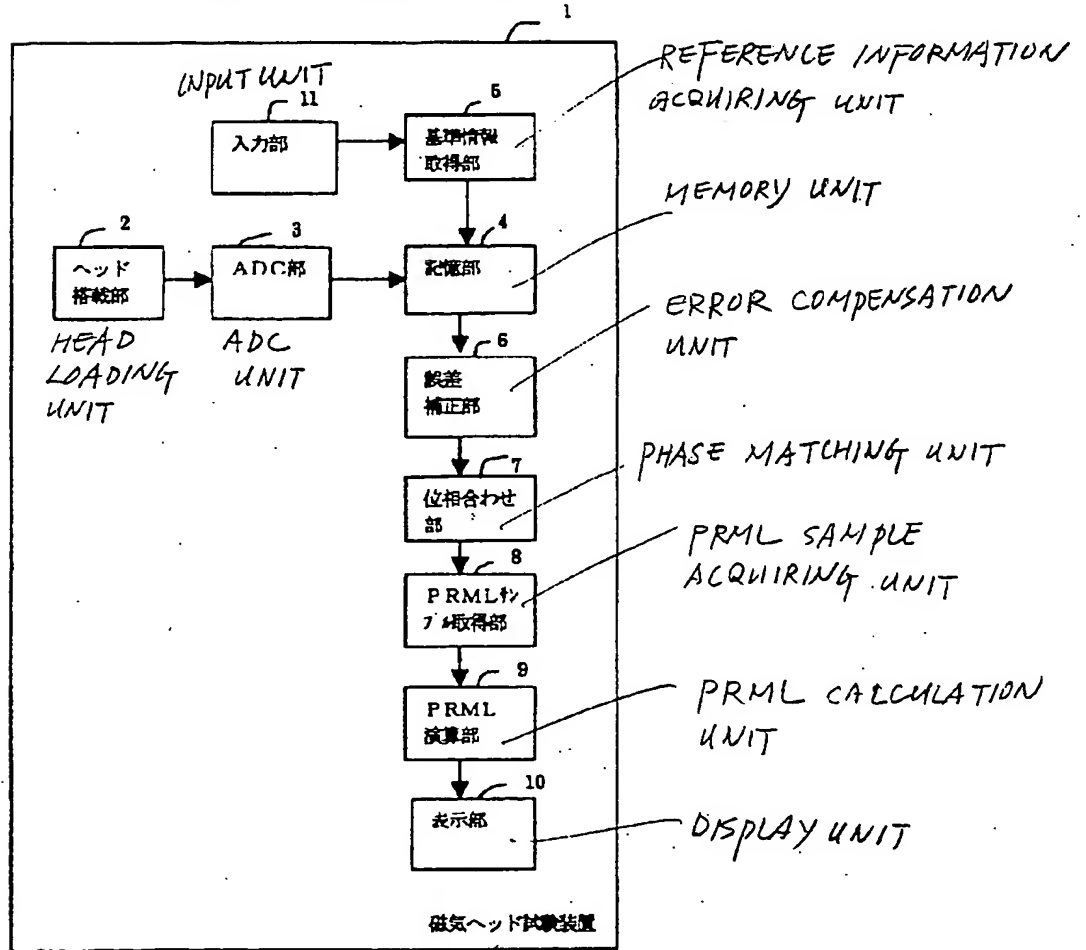


Fig. 1

STRUCTURAL DIAGRAM OF MAGNETIC HEAD TESTING

実施例の磁気ヘッド試験装置の構成図

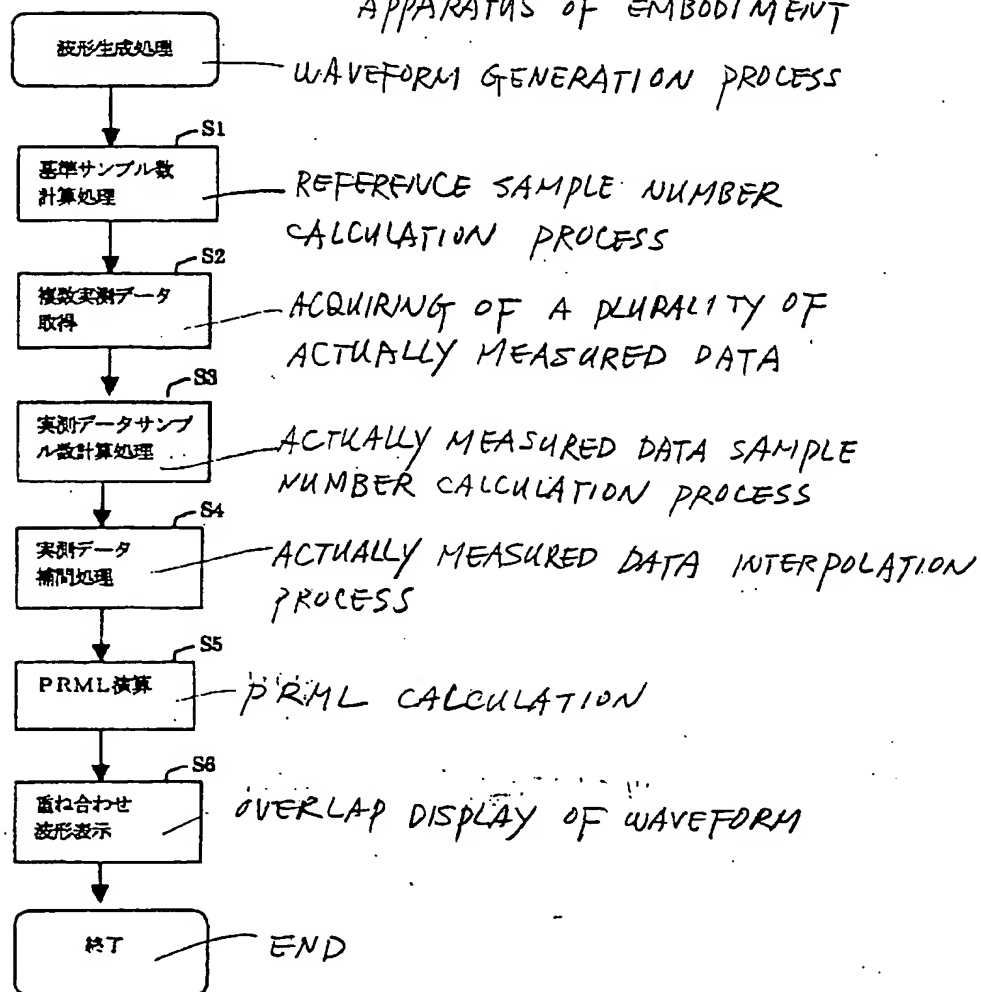
APPARATUS OF THE EMBODIMENT



MAGNETIC HEAD TESTING APPARATUS

Fig. 2

FLOW DIAGRAM OF PROCESS
OF MAGNETIC HEAD TESTING
APPARATUS OF EMBODIMENT



EMBODIMENT

POSTAMBLE PART

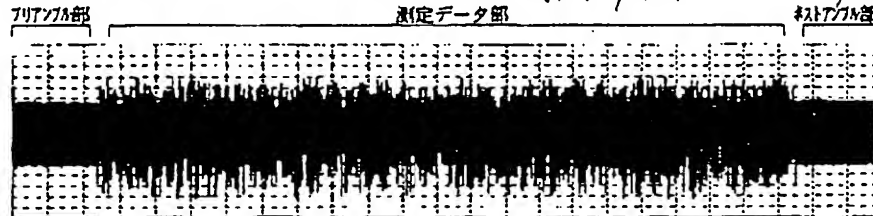
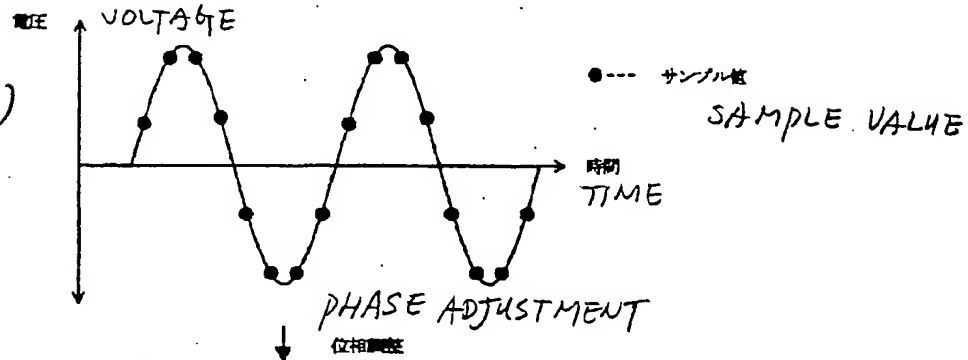


Fig. 3

DIAGRAM FOR EXPLAINING ADC SAMPLE OF EMBODIMENT

ADC ASYNCHRONOUS SAMPLING

(a) ADC非同相サンプリング



(b) 同期リサンプリング

SYNCHRONOUS SAMPLING

電圧
VOLTAGE

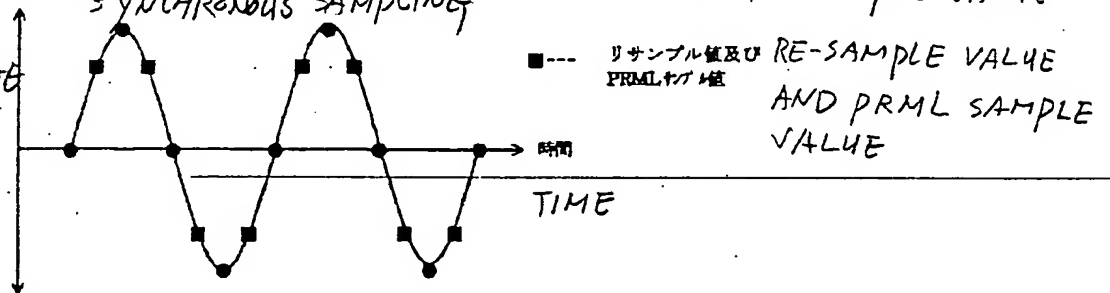
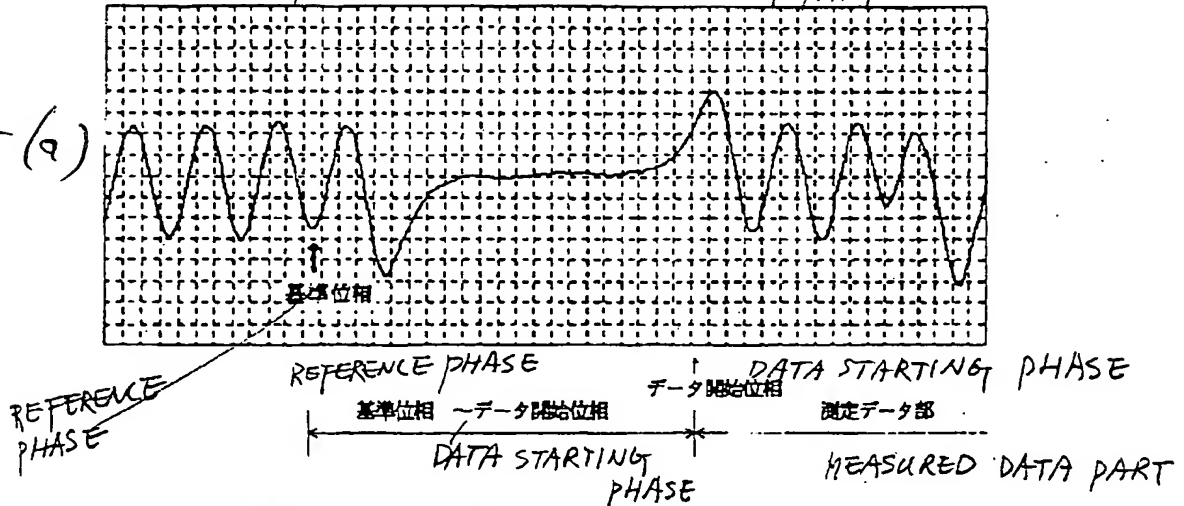


DIAGRAM FOR EXPLAINING DATA
 STARTING PHASE/ENDING PHASE
 OF EMBODIMENT

PREAMBLE ENDING PART ~ MEASURED DATA LEADING PART

Fig. 5 (a)



MEASURED
 DATA ENDING
 PART

Fig. 5 (b)

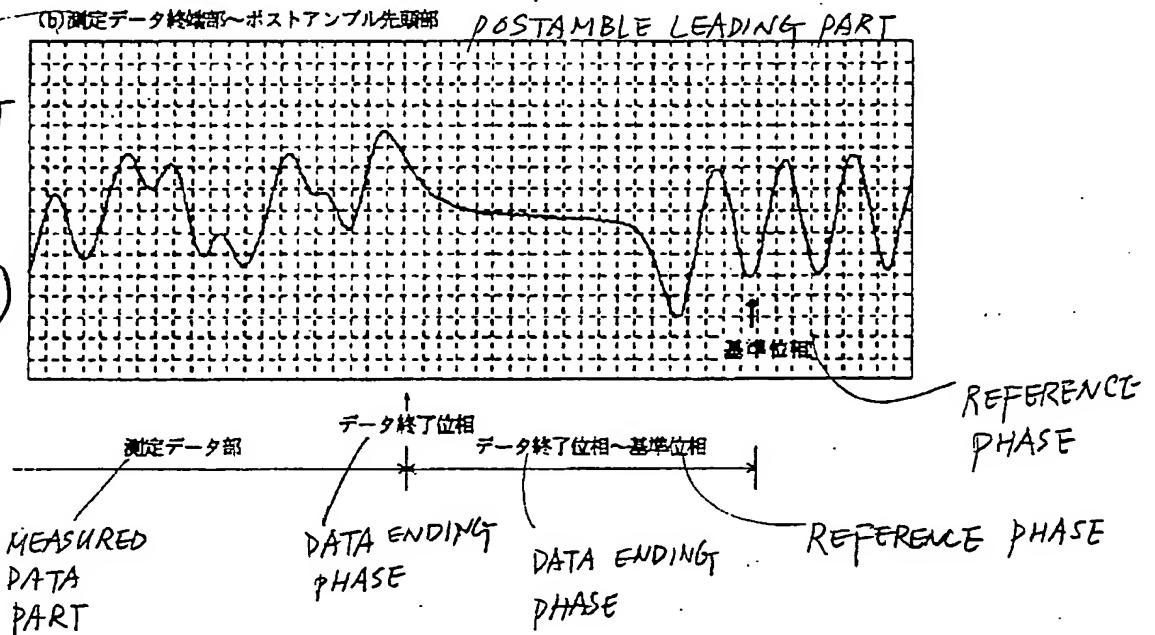


DIAGRAM FOR EXPLAINING
PHASE MATCHING OF EMBODIMENT

Fig 6 (a) (a)基準波形よりも
データ数が多い
場合

NUMBER OF DATA IS
LARGER THAN THAT OF
THE REFERENCE WAVEFORM

↓ データ数が基準波形と同じになるように引き

NUMBER OF DATA IS
THINNED TO BECOME
EQUAL TO THAT OF
THE REFERENCE
WAVEFORM.

Fig. 6 (b) (b)基準 (理想) 波形
REFERENCE (IDEAL)
WAVEFORM

↑ データ数が基準波形と同じになるように補間する

NUMBER OF DATA IS
INTERPOLATED TO
BECOME EQUAL TO
THAT OF THE
REFERENCE WAVEFORM.

Fig. 6 (c) (c)基準波形よりも
データ数が少ない
場合

NUMBER OF DATA IS
SMALLER THAN THAT OF
THE REFERENCE WAVEFORM

DIAGRAM FOR EXPLAINING INTERPOLATION PROCESS OF EMBODIMENT

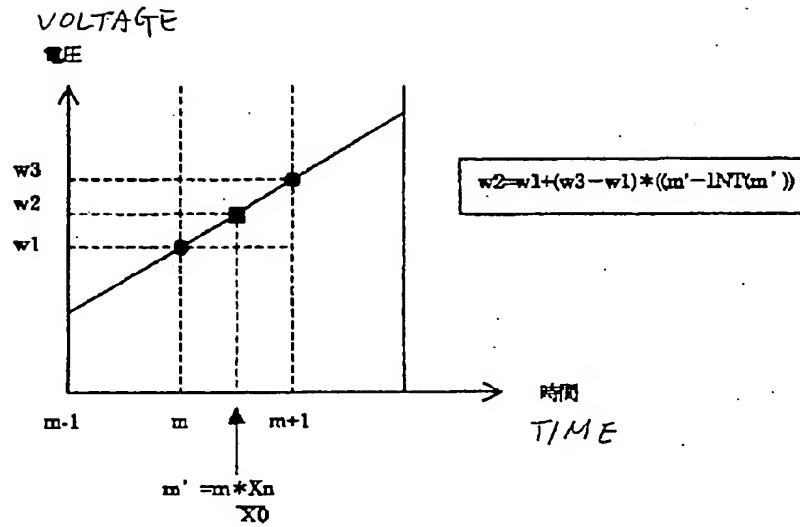


Fig. 7

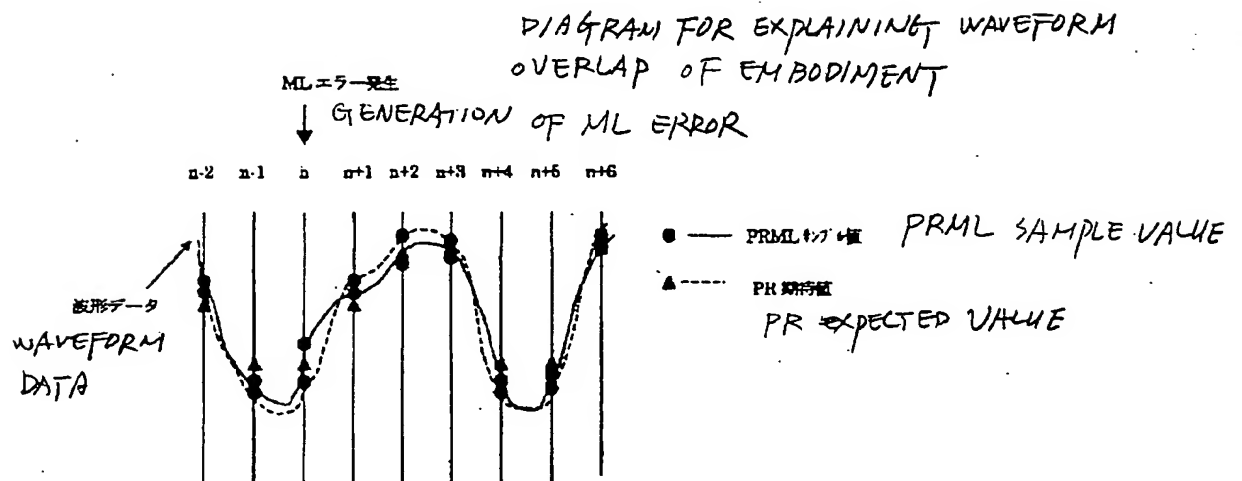


Fig. 8

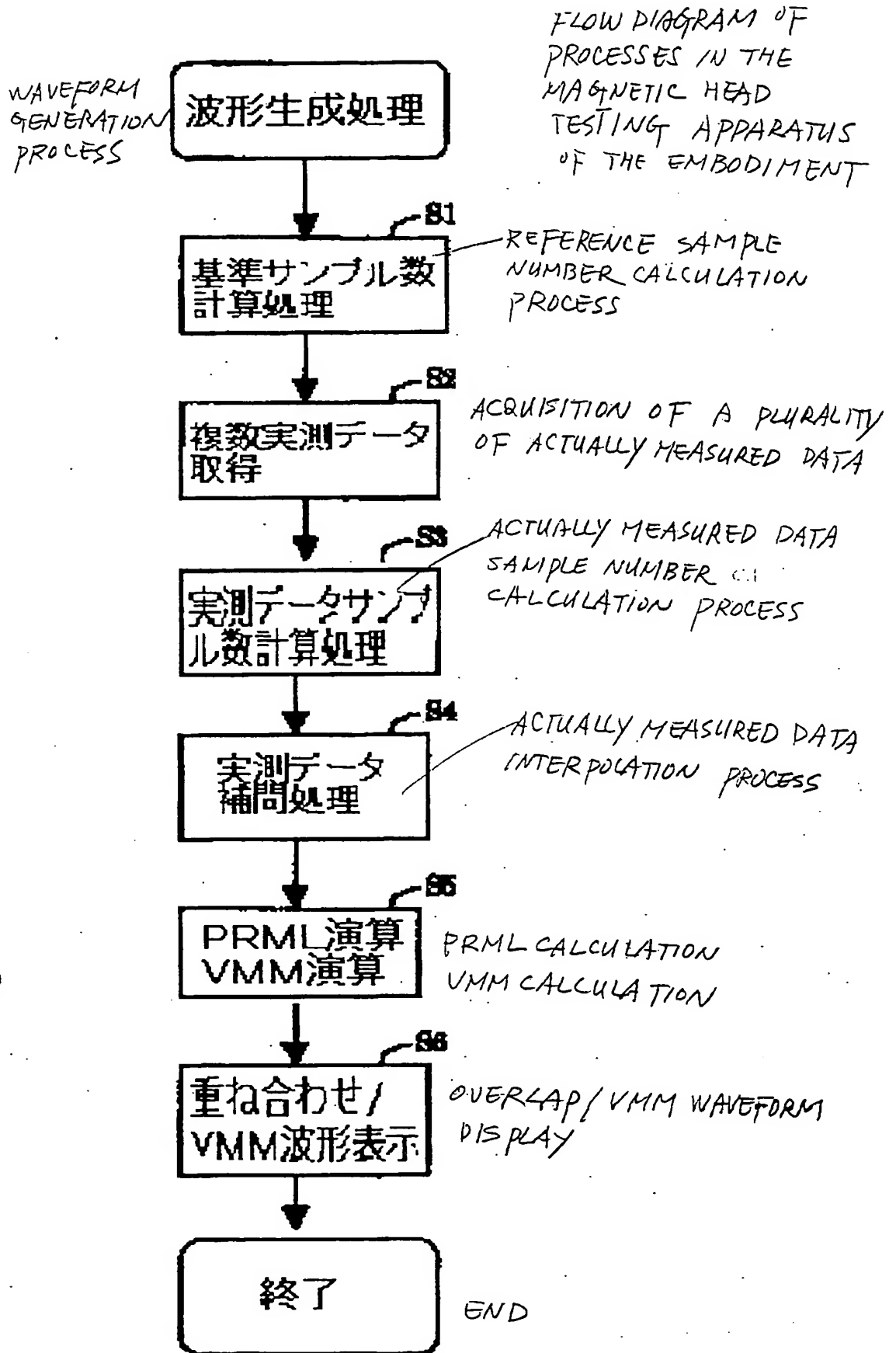


DIAGRAM FOR EXPLAINING
 VMM WORST 50 OF
 EMBODIMENT

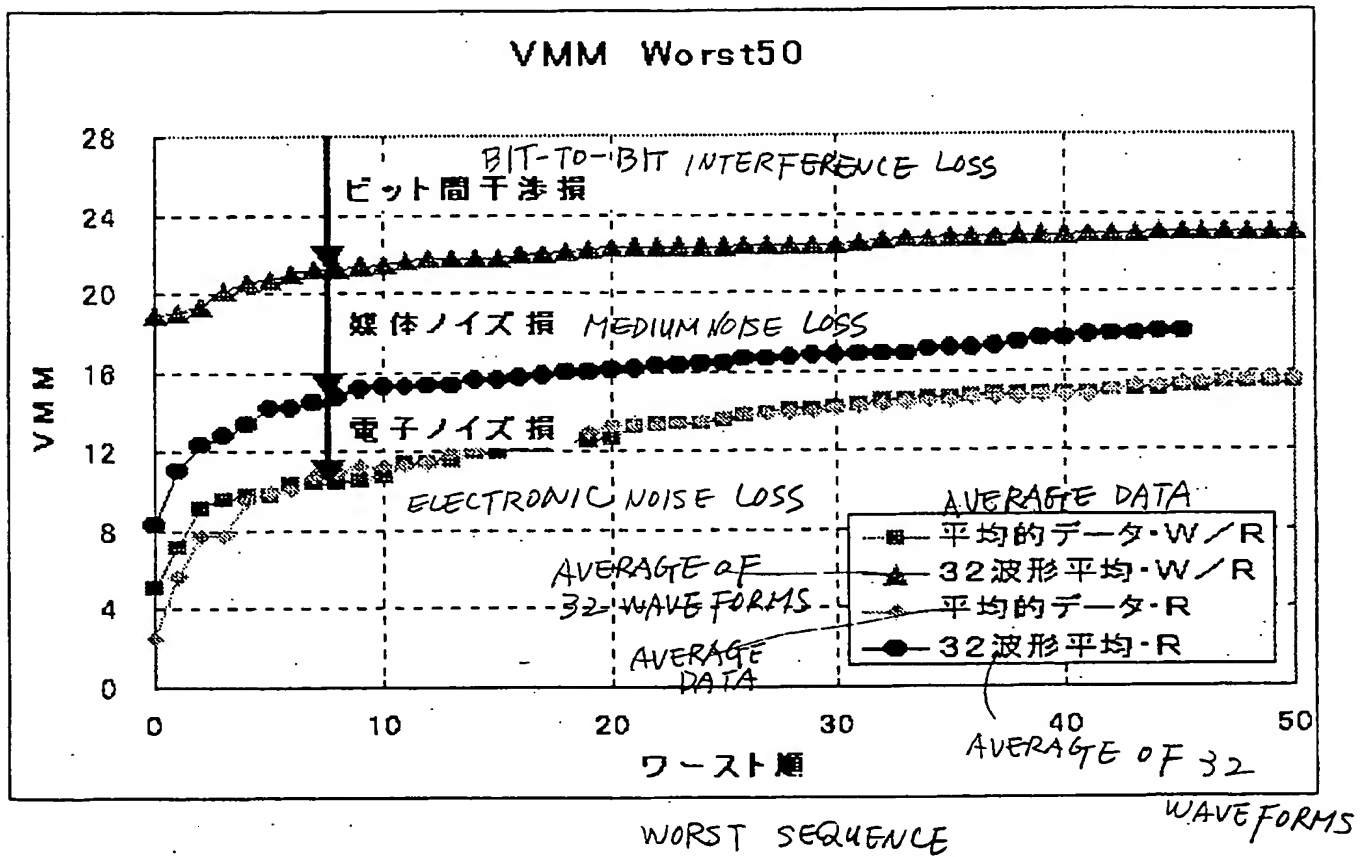


Fig. 10